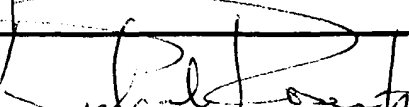


FORM PTO-1449			Atty. Docket No. SEN-002		Serial No. 09/927,102	
LIST OF PRIOR ART CITED BY APPLICANT			Applicant: Michael Weber-Grabau et al.		Filing Date: August 10, 2001	
					Group: 2877	
U.S. PATENT DOCUMENTS						
Examiner Initial*	Document Number	Grant Date	Name	Class	Sub Class	Filing Date
AA	5,233,191	8/3/93	Noguchi et al.	250	306	4/2/91
AB	5,459,404	10/17/95	Josephs	324	751	3/28/94
AC	5,994,914	11/30/99	Tsuruta	324	765	7/25/97
AD						
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AH						
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FOREIGN PATENT DOCUMENTS						
Examiner Initial*	Document Number	Publ. Date	Country	Class	Sub Class	Translation Yes No
AK	0 991 918	4/12/00	EPO			
AL	63 086429	4/16/88	Japan			X
AM						
AN						
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
AO						
AP						
AQ						
EXAMINER: 				DATE CONSIDERED: 7/23/03		
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				Filing Date: August 10, 2001		Group: 2877	
U.S. PATENT DOCUMENTS							
Examiner Initial*	Document Number	Grant Date	Name		Class	Sub Class	Filing Date
M	BA	5,957,749	Finarov		451	6	
fu	BB	5,991,022	Buermann et al.		356	319	
	BC						
	BD						
	BE						
	BF						
	BG						
	BH						
	BI						
	BJ						
FOREIGN PATENT DOCUMENTS							
Examiner Initial*	Document Number	Grant Date	Country	Class	Sub Class	Translation Yes No	
	BK						
	BL						
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	BM						
	BN						
	BO						
EXAMINER: <i>Richard [Signature]</i>				DATE CONSIDERED: 9/23/03			
*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



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				Filing Date: August 10, 2001		Group: 2877	
U.S. PATENT DOCUMENTS							
Examiner Initial*	Document Number	Grant Date	Name		Class	Sub Class	Filing Date
<i>Rm</i>	AA	5,067,805	11/26/91 Corle et al.		359	235	
<i>Rm</i>	AB	5,486,701	01/23/96 Norton et al.		250	372	
<i>Rm</i>	AC	5,517,312	05/14/96 Finarov		356	386	
<i>Rm</i>	AD	5,608,526	03/04/97 Piwonka-Corle et al.		356	369	
<i>Rm</i>	AE	5,682,242	10/28/97 Eylon		356	401	
<i>Rm</i>	AF	5,747,813	05/05/98 Norton et al.		250	372	
<i>Rm</i>	AG	5,859,424	01/12/99 Norton et al.		250	226	
<i>Rm</i>	AH	5,885,045	03/23/99 Rush		414	417	
<i>Rm</i>	AI	5,889,593	03/30/99 Bareket		356	445	
<i>Rm</i>	AJ	5,943,122	08/24/99 Holmes		356	73	
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Examiner Initial*	Document Number	Grant Date	Country	Class	Sub Class	Translation Yes No	
<i>Rm</i>	AK	EP0973068	EPO			X	
<i>Rm</i>	AL	EP0973069	EPO			X	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>Rm</i>	AM	Nanometrics News Release, "Applied Materials/Nanometrics Sign Pact For Metrology Integration", Copyright 1998 Worldwide Videotex, Electro Manufacturing, Nov. 1998, No. 11, Vol. 11.					
	AN						
	AO						
EXAMINER: <i>[Signature]</i>				DATE CONSIDERED: 9/23/03			
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